TEST REPORT

FCC PART 15 SUBPART C 15.247

Test report

On Behalf of

Shenzhen XinHuaMei Electronics Limited Company

For

Bluetooth Speaker

Model No.: BTS-637, DP-3098, SP832

FCC ID: R8HBTS-637

Prepared for : Shenzhen XinHuaMei Electronics Limited Company

Bldg 5, Taifeng Industrial Park, No.10, Jianan Road, Shajing Sub-district, Baoan District, Shenzhen, China

Prepared By : Shenzhen HUAK Testing Technology Co., Ltd.

1-2/F,Building19,JunfengIndustrialPark,ChongqingRoad,HepingCommunity,FuhaiStreet,Bao'anDistrict,Shenzhen,Guangdong,China

Date of Test: Jan. 18, 2019 to Jan. 24, 2019

Date of Report: Jan. 24, 2019

Report Number: HK1901230222E

TEST RESULT CERTIFICATION

Applicant's name..... Shenzhen XinHuaMei Electronics Limited Company

Address..... Bldg 5, Taifeng Industrial Park, No.10, Jianan Road, Shajing Sub-district, Baoan District, Shenzhen, China

Manufacture's Name ..... Shenzhen XinHuaMei Electronics Limited Company

Address..... Bldg 5, Taifeng Industrial Park, No.10, Jianan Road, Shajing Sub-district, Baoan District, Shenzhen, China

Product description

Trade Mark: N/A

Product name..... Bluetooth Speaker

Model and/or type reference ... BTS-637, DP-3098, SP832

Difference description All the same except for the model name

Standards..... **47 CFR FCC Part 15 Subpart C 15.247**

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Date of Test..... :

Date (s) of performance of tests..... : Jan. 18, 2019 ~ Jan. 24, 2019

Date of Issue ..... : Jan. 24, 2019

Test Result ..... : **Pass**

Testing Engineer : Gary Qian

(Gary Qian)

Technical Manager : Eden Hu

(Eden Hu)

Authorized Signatory : Jason Zhou

(Jason Zhou)

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1.SUMMARY

1.1. TEST STANDARDS

The tests were performed according to following standards:

FCC Rules Part 15.247: Frequency Hopping, Direct Spread Spectrum and Hybrid Systems that are in operation within the bands of 902-928 MHz, 2400-2483.5 MHz, and 5725-5850 MHz

ANSI C63.10:2013 : American National Standard for Testing Unlicensed Wireless Devices

1.2. Test Description

FCC PART 15.247		
FCC Part 15.207	AC Power Conducted Emission	PASS
FCC Part 15.247(a)(1)(i)	20dB Bandwidth	PASS
FCC Part 15.247(d)	Spurious RF Conducted Emission	PASS
FCC Part 15.247(b)	Maximum Peak Output Power	PASS
FCC Part 15.247(b)	Pseudorandom Frequency Hopping Sequence	PASS
FCC Part 15.247(a)(1)(iii)	Number of hopping frequency& Time of Occupancy	PASS
FCC Part 15.247(a)(1)	Frequency Separation	PASS
FCC Part 15.205/15.209	Radiated Emissions	PASS
FCC Part 15.247(d)	Band Edge Compliance of RF Emission	PASS

Test Facility

1.3.1 Address of the test laboratory

Shenzhen HUAK Testing Technology Co., Ltd.
Add.:1F, B2 Building, Junfeng Zhongcheng Zhizao Innovation Park,Heping Community, Fuhai Street, Bao'an District, Shenzhen, China

There is one 3m semi-anechoic chamber and two line conducted labs for final test. The Test Sites meet the requirements in documents ANSI C63.4 and CISPR 32/EN 55032 requirements.

1.3.2 Laboratoryaccreditation

The test facility is recognized, certified, or accredited by the following organizations:

IC Registration No.: 21210

The 3m alternate test site of Shenzhen HUAK Testing Technology Co., Ltd. EMC Laboratory has been registered by Certification and Engineer Bureau of Industry Canada for the performance of with Registration No.: 21210 on May 24, 2016.

FCC Registration No.: CN1229
Test Firm Registration Number : 616276

1.3. Statement of the measurement uncertainty

The data and results referenced in this document are true and accurate. The reader is cautioned that there may be errors within the calibration limits of the equipment and facilities. The measurement uncertainty was calculated for all measurements listed in this test report acc. to CISPR 16 - 4 “Specification for radio disturbance and immunity measuring apparatus and methods – Part 4: Uncertainty in EMC Measurements“ and is documented in the Shenzhen HUAK Testing Technology Co., Ltd.quality system acc. to DIN EN ISO/IEC 17025. Furthermore, component and process variability of devices similar to that tested may result in additional deviation. The manufacturer has the sole responsibility of continued compliance of the device.

Hereafter the best measurement capability for HUAK laboratory is reported:

Test	Measurement Uncertainty	Notes
Transmitter power conducted	±0.57 dB	(1)
Transmitter power Radiated	±2.20 dB	(1)
Conducted spurious emission 9KHz-40 GHz	±2.20 dB	(1)
Occupied Bandwidth	±0.01ppm	(1)
Radiated Emission30~1000MHz	±4.10dB	(1)
Radiated Emission Above 1GHz	±4.32dB	(1)
Conducted Disturbance0.15~30MHz	±3.20dB	(1)

(1) This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

2. GENERAL INFORMATION

2.1. Environmental conditions

During the measurement the environmental conditions were within the listed ranges:

Normal Temperature:	25°C
Relative Humidity:	55 %
Air Pressure:	101 kPa

2.2. General Description of EUT

Product Name:	Bluetooth Speaker
Model/Type reference:	BTS-637
Power supply:	DC 3.7V by battery
Version:	V4.2
Modulation:	GFSK, π/4DQPSK
Operation frequency:	2402MHz~2480MHz
Channel number:	79
Channel separation:	1MHz
Antenna type:	PCB Antenna
Antenna gain:	-0.58dBi
Hardware Version:	V3.1
Software Version:	V4.2

Note: For more details, refer to the user's manual of the EUT.

2.3. Description of Test Modes and Test Frequency

The Applicant provides communication tools software to control the EUT for staying in continuoustransmitting and receiving mode for testing.
There are79 channels provided to the EUT and Channel 00/39/78 was selected for testing.

Operation Frequency：

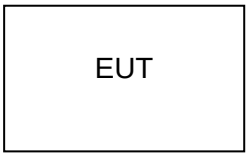
Channel	Frequency (MHz)
00	2402
01	2403
⋮	⋮
38	2440
39	2441
40	2442
⋮	⋮
77	2479
78	2480

Note: The line display in grey were the channel selected for testing

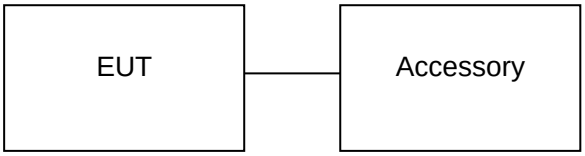
NO.	TEST MODE DESCRIPTION
1	Low channel TX
2	Middle channel TX
3	High channel TX
4	Normal Operating (BT)

Note:
1.Only the result of the worst case was recorded in the report, if no other cases.
2. For Radiated Emission, 3axis were chosen for testing for each applicable mode.

Conducted Emission Configure :



Radiated Emission Configure :



Item	Equipment	Model No.	ID or Specification	Remark
1	Adapter	NTR-S01	DC 5V	Support

2.4. Related Submittal(s) / Grant (s)

This submittal(s) (test report) is intended to comply with Section 15.247 of the FCC Part 15, Subpart C Rules.

2.5. Modifications

No modifications were implemented to meet testing criteria.

2.6. Receiver Input Bandwidth

The input bandwidth of the receiver is 1.3MHZ,In every connection one Bluetooth device is the master and the other one is slave. The master determines the hopping sequence. The slave follows this sequence. Both devices shift between RX and TX time slot according to the clock of the master. Additionally the type of connection(e.g. single of multislot packet) is set up at the beginning of the connection. The master adapts its hopping frequency and its TX/RX timing according to the packet type of the connection. Also the slave of the connection will use these settings.
Repeating of a packet has no influence on the hopping sequence. The hopping sequence generated by the master of the connection will be followed in any case. That means, a repeated packet will not be send on the same frequency, it is send on the next frequency of the hopping sequence.

2.7. Example of a Hopping Sequence in Data Mode

Example of a 79 hopping sequence in data mode:
40,21,44,23,42,53,46,55,48,33,52,35,50,65,54,67
56,37,60,39,58,69,62,71,64,25,68,27,66,57,70,59
72,29,76,31,74,61,78,63,01,41,05,43,03,73,07,75
09,45,13,47,11,77,15,00,64,49,66,53,68,02,70,06
01,51,03,55,05,04

2.8. Equally Average Use of Frequencies and Behaviour

The generation of the hopping sequence in connection mode depends essentially on two input values:
1. LAP/UAP of the master of the connection.
2. Internal master clock
The LAP(lower address part) are the 24 LSB's of the 48 BD_ADDRESS. The BD_ADDRESS isan unambiguous number of every Bluetooth unit. The UAP(upper address part) are the 24MSB's of the 48BD_ADDRESS
The internal clock of a Bluetooth unit is derived from a free running clock which is never adjusted and is never turned off. For ehavior zation with other units only offset are used. It has no relation to the timeof the day. Its resolution is at least half the RX/TX slot length of 312.5us.The clock has a cycle of aboutone day(23h30).In most case it is implemented as 28 bit counter. For the deriving of the hopping sequence the entire.LAP(24 bits),4LSB's(4bits)(Input 1) and the 27MSB's of the clock(Input 2) are used. With this input values different mathematical procedures(permutations, additions, XOR-operations)are performed to generate teSequence. This will be done at the beginning of every new transmission.
Regarding short transmissions the Bluetooth system has the following8ehavior:
The first connection between the two devices is established, a hopping sequence was generated. For Transmitting the wanted data the complete hopping sequence was not used. The connection ended.
The second connection will be established. A new hopping sequence is generated. Due to the fact the Bluetooth clock has a different value, because the period between the two transmission is longer(and it Cannot be shorter) than the minimum resolution of the clock(312.5us).The hopping sequence will always Differ from the first one.

2.9. Equipment Used

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	L.I.S.N. Artificial Mains Network	R&S	ENV216	HKE-002	Dec. 27, 2018	1 Year
2.	Receiver	R&S	ESCI 7	HKE-010	Dec. 27, 2018	1 Year
3.	RF automatic control unit	Tonscend	JS0806-2	HKE-060	Dec. 27, 2018	1 Year
4.	Spectrum analyzer	R&S	FSP40	HKE-025	Dec. 27, 2018	1 Year
5.	Spectrum analyzer	Agilent	N9020A	HKE-048	Dec. 27, 2018	1 Year
6.	Preamplifier	Schwarzbeck	BBV 9743	HKE-006	Dec. 27, 2018	1 Year
7.	EMI Test Receiver	Rohde & Schwarz	ESCI 7	HKE-010	Dec. 27, 2018	1 Year
8.	Bilog Broadband Antenna	Schwarzbeck	VULB9163	HKE-012	Dec. 27, 2018	1 Year
9.	Loop Antenna	Schwarzbeck	FMZB 1519 B	HKE-014	Dec. 27, 2018	1 Year
10.	Horn Antenna	Schewarzbeck	9120D	HKE-013	Dec. 27, 2018	1 Year
11.	Pre-amplifier	EMCI	EMC051845 SE	HKE-015	Dec. 27, 2018	1 Year
12.	Pre-amplifier	Agilent	83051A	HKE-016	Dec. 27, 2018	1 Year
13.	EMI Test Software EZ-EMC	Tonscend	JS1120-B Version	HKE-083	Dec. 27, 2018	N/A
14.	Power Sensor	Agilent	E9300A	HKE-086	Dec. 27, 2018	1 Year
15.	Spectrum analyzer	Agilent	N9020A	HKE-048	Dec. 27, 2018	1 Year
16.	Signal generator	Agilent	N5182A	HKE-029	Dec. 27, 2018	1 Year
17.	Signal Generator	Agilent	83630A	HKE-028	Dec. 27, 2018	1 Year
18.	Shielded room	Shiel Hong	4*3*3	HKE-039	Dec. 27, 2018	3 Year

The calibration interval was one year

3. Peak Output Power

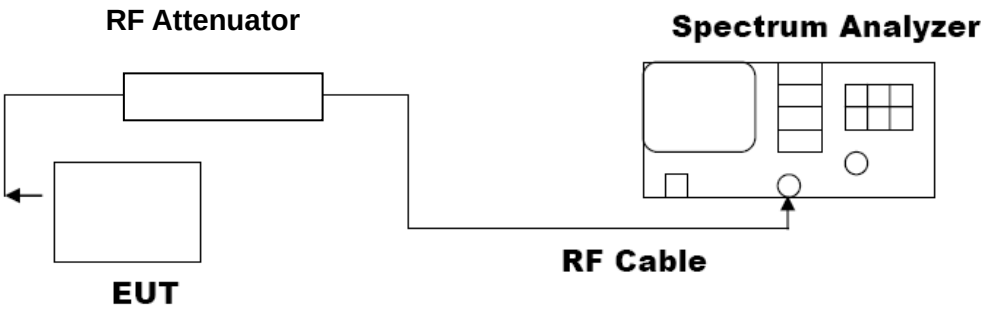
3.1. Measurement Procedure

For peak power test:

1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
2. Span: Approximately five times the 20 dB bandwidth, centered on a hopping channel.
3. RBW > 20 dB bandwidth of the emission being measured.
4. VBW ⩾RBW.
5. Sweep: Auto.
6. Detector function: Peak.
7. Trace: Max hold.

Allow trace to stabilize. Use the marker-to-peak function to set the marker to the peak of the emission. The indicated level is the peak output power, after any corrections for external attenuators and cables.

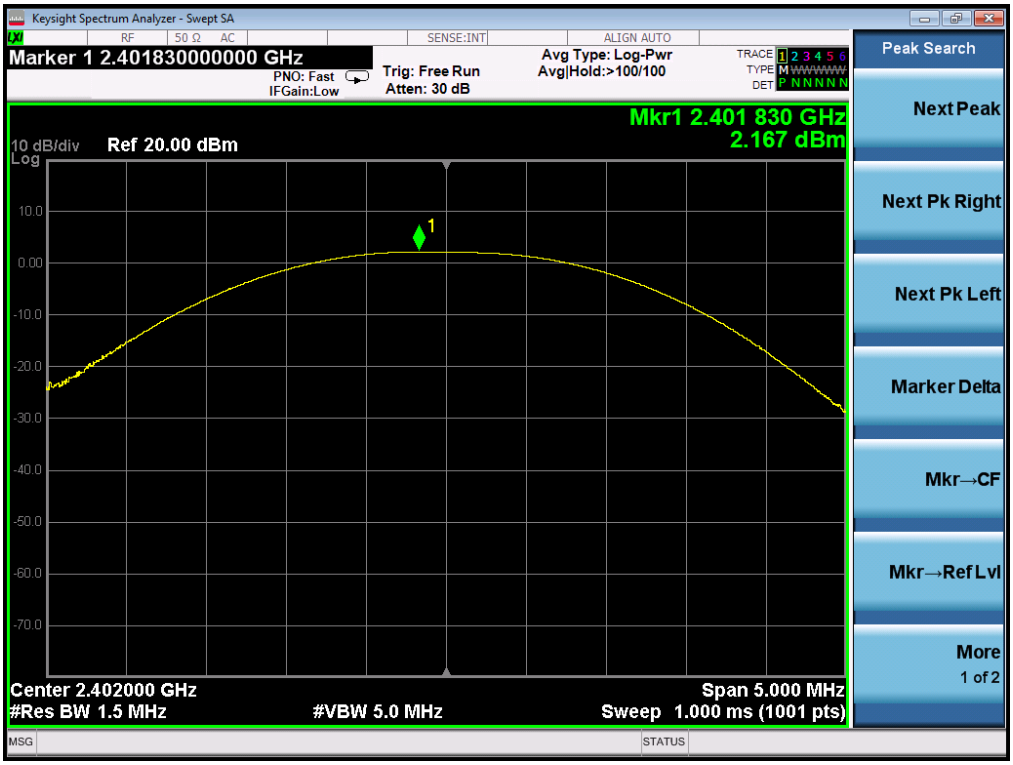
3.2. Test Set-Up (Block Diagram of Configuration)



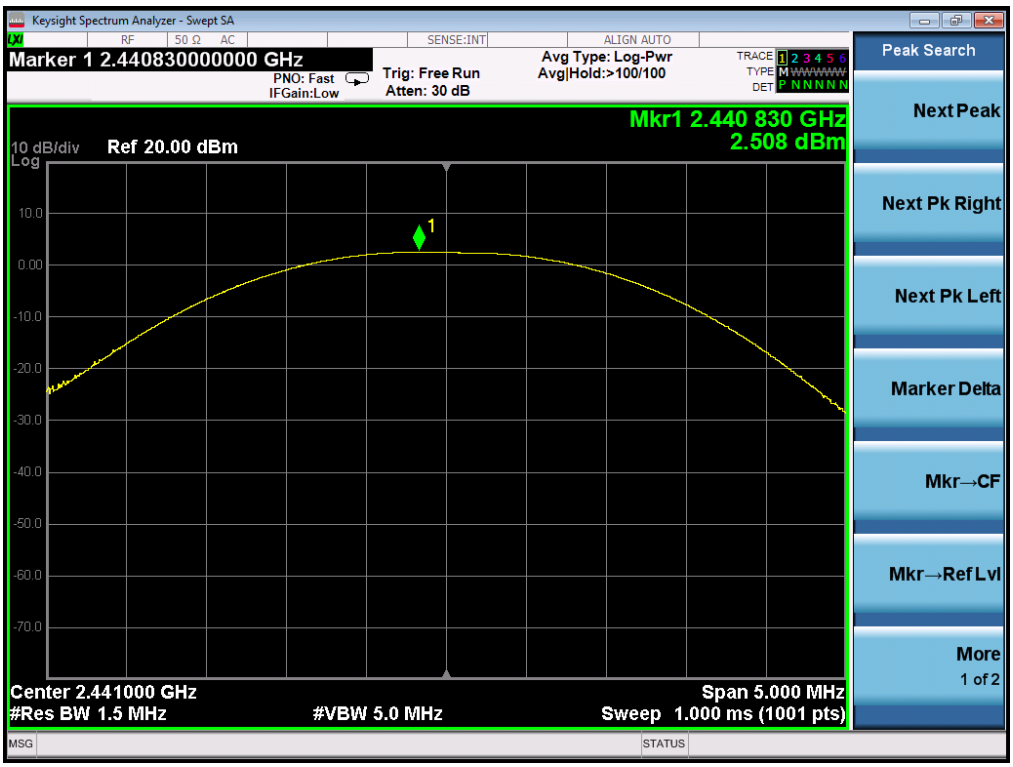
3.3. Limits and Measurement Result

PEAK OUTPUT POWER MEASUREMENT RESULT FOR GFSK MOUDULATION			
Frequency (GHz)	Peak Power (dBm)	Applicable Limits (dBm)	Pass or Fail
2.402	2.167	30	Pass
2.441	2.508	30	Pass
2.480	2.463	30	Pass

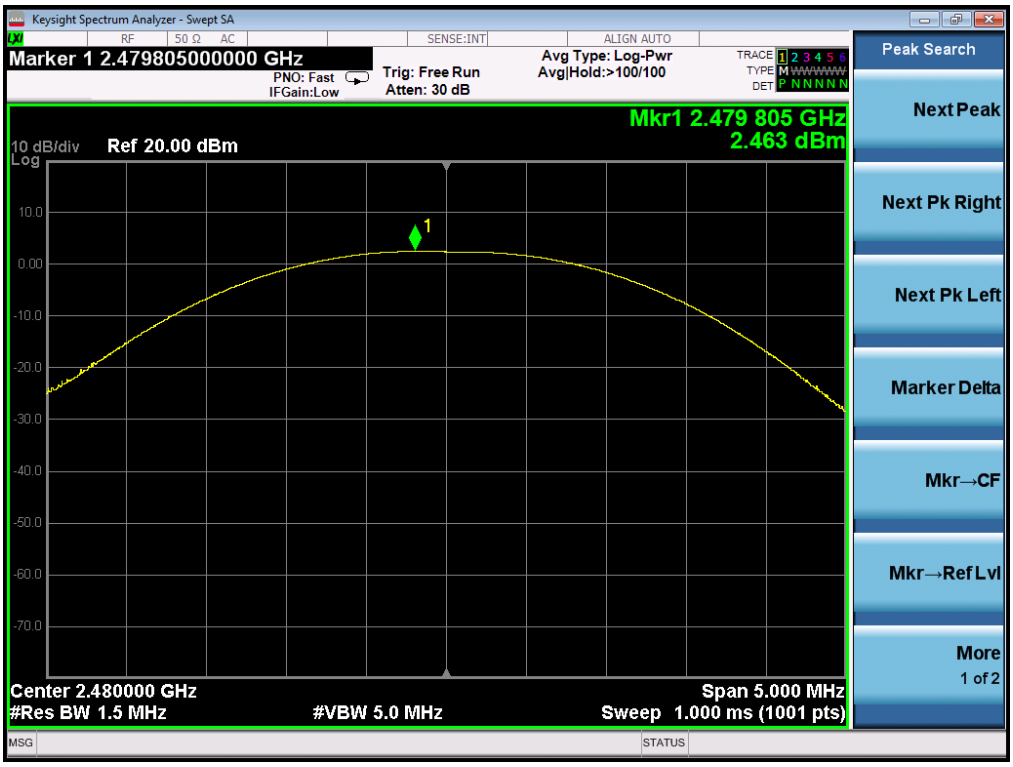
CH0



CH39


Keysight Spectrum Analyzer - Swept SA
Marker 1 2.440830000000 GHz
PNO: Fast
IFGain:Low
Trig: Free Run
Atten: 30 dB
Avg Type: Log-Pwr
Avg|Hold:>100/100
Mkr1 2.440 830 GHz
2.508 dBm
10 dB/div Ref 20.00 dBm
Log
Center 2.441000 GHz
#Res BW 1.5 MHz
#VBW 5.0 MHz
Span 5.000 MHz
Sweep 1.000 ms (1001 pts)
Peak Search
Next Peak
Next Pk Right
Next Pk Left
Marker Delta
Mkr→CF
Mkr→Ref Lvl
More
1 of 2

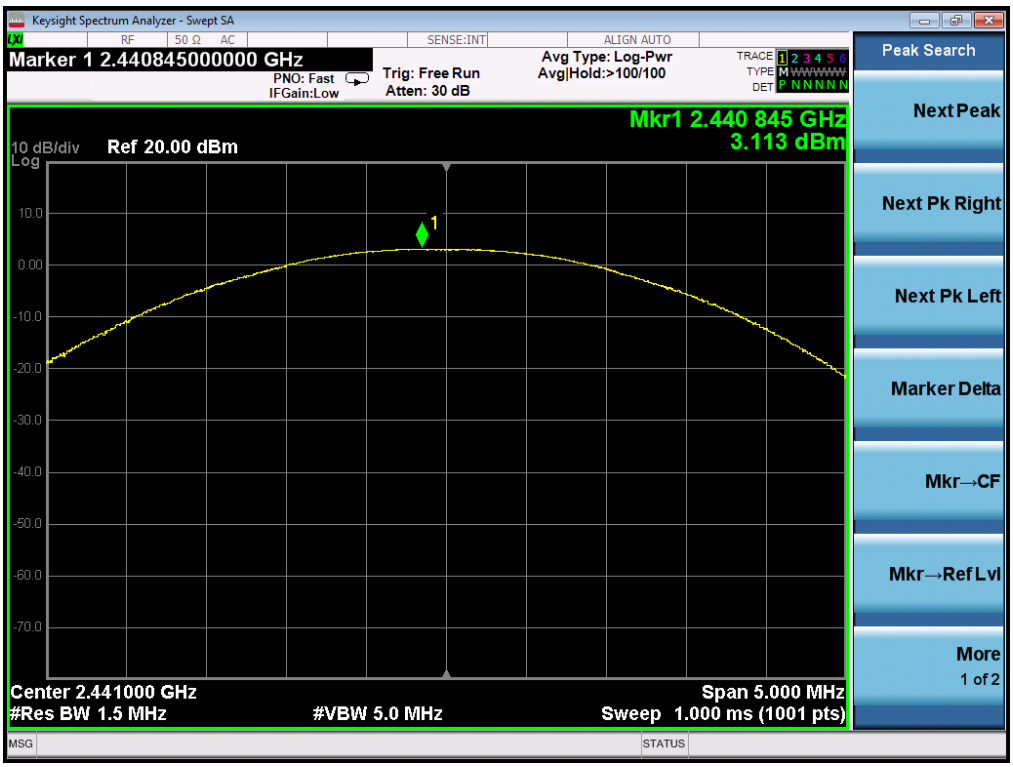
CH78


Keysight Spectrum Analyzer - Swept SA
Marker 1 2.479805000000 GHz
PNO: Fast
IFGain:Low
Trig: Free Run
Atten: 30 dB
Avg Type: Log-Pwr
Avg|Hold:>100/100
Mkr1 2.479 805 GHz
2.463 dBm
10 dB/div Ref 20.00 dBm
Log
Center 2.480000 GHz
#Res BW 1.5 MHz
#VBW 5.0 MHz
Span 5.000 MHz
Sweep 1.000 ms (1001 pts)
Peak Search
Next Peak
Next Pk Right
Next Pk Left
Marker Delta
Mkr→CF
Mkr→Ref Lvl
More
1 of 2

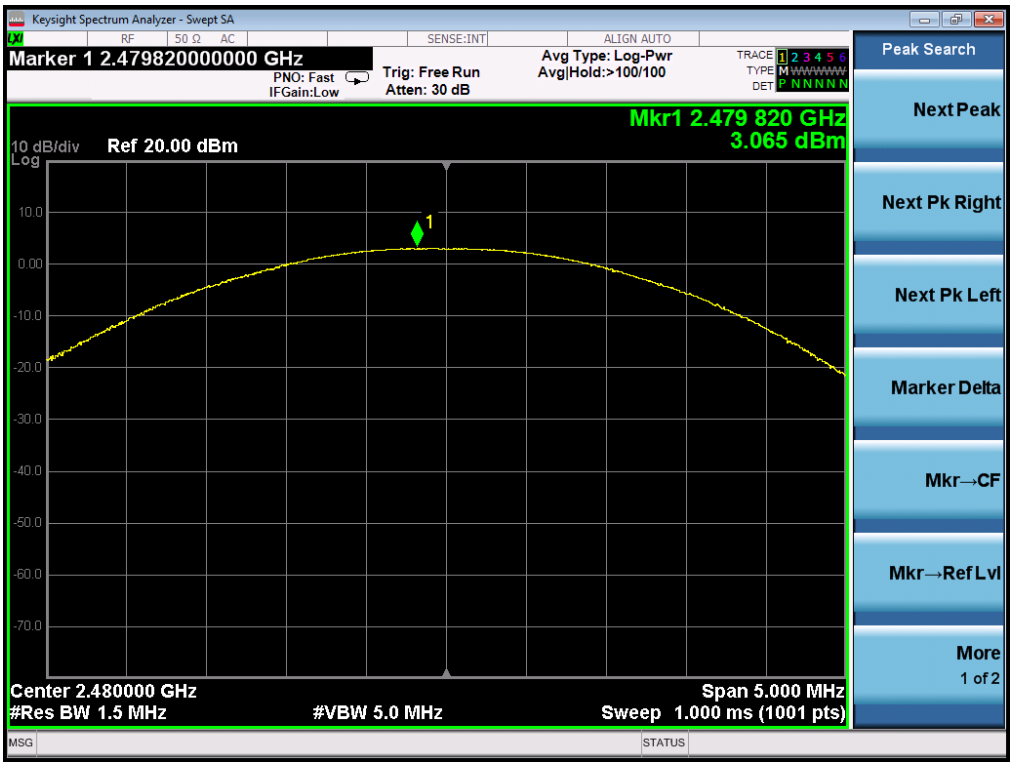
PEAK OUTPUT POWER MEASUREMENT RESULT FOR Π/4-DQPSK MODULATION			
Frequency (GHz)	**Peak Power (dBm)**	**Applicable Limits (dBm)**	**Pass or Fail**
2.402	2.764	30	Pass
2.441	3.113	30	Pass
2.480	3.065	30	Pass

CH0

CH39


Keysight Spectrum Analyzer - Swept SA
Marker 1 2.440845000000 GHz
PNO: Fast
IFGain:Low
Trig: Free Run
Atten: 30 dB
Avg Type: Log-Pwr
Avg|Hold:>100/100
Mkr1 2.440 845 GHz
3.113 dBm
10 dB/div
Log
Ref 20.00 dBm
Center 2.441000 GHz
#Res BW 1.5 MHz
#VBW 5.0 MHz
Span 5.000 MHz
Sweep 1.000 ms (1001 pts)
Peak Search
Next Peak
Next Pk Right
Next Pk Left
Marker Delta
Mkr→CF
Mkr→Ref Lvl
More
1 of 2

CH78

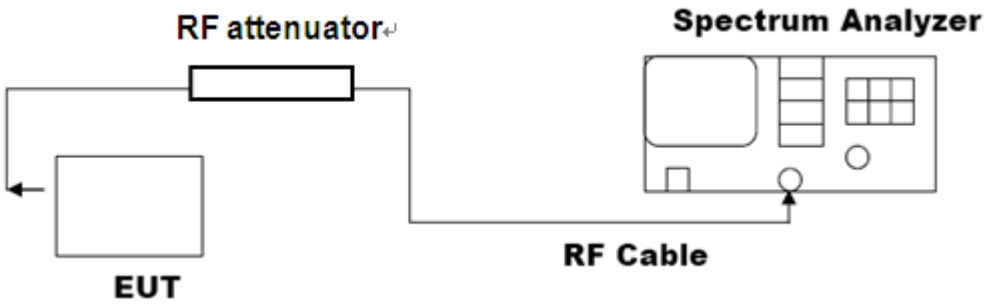

Keysight Spectrum Analyzer - Swept SA
Marker 1 2.479820000000 GHz
PNO: Fast
IFGain:Low
Trig: Free Run
Atten: 30 dB
Avg Type: Log-Pwr
Avg|Hold:>100/100
Mkr1 2.479 820 GHz
3.065 dBm
10 dB/div
Log
Ref 20.00 dBm
Center 2.480000 GHz
#Res BW 1.5 MHz
#VBW 5.0 MHz
Span 5.000 MHz
Sweep 1.000 ms (1001 pts)
Peak Search
Next Peak
Next Pk Right
Next Pk Left
Marker Delta
Mkr→CF
Mkr→Ref Lvl
More
1 of 2

4. 20dB Bandwidth

4.1. Measurement Procedure

1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
2, Set the EUT Work on the top, the middle and the bottom operation frequency individually.
3. Set Span = approximately 2 to 5 times the 20 dB bandwidth, centered on a hoping channel
   The nominal IF filter bandwidth (3 dB RBW) shall be in the range of 1% to 5% of the OBW and video bandwidth (VBW) shall be approximately three times RBW; Sweep = auto; Detector function = peak
4. Set SPA Trace 1 Max hold, then View.

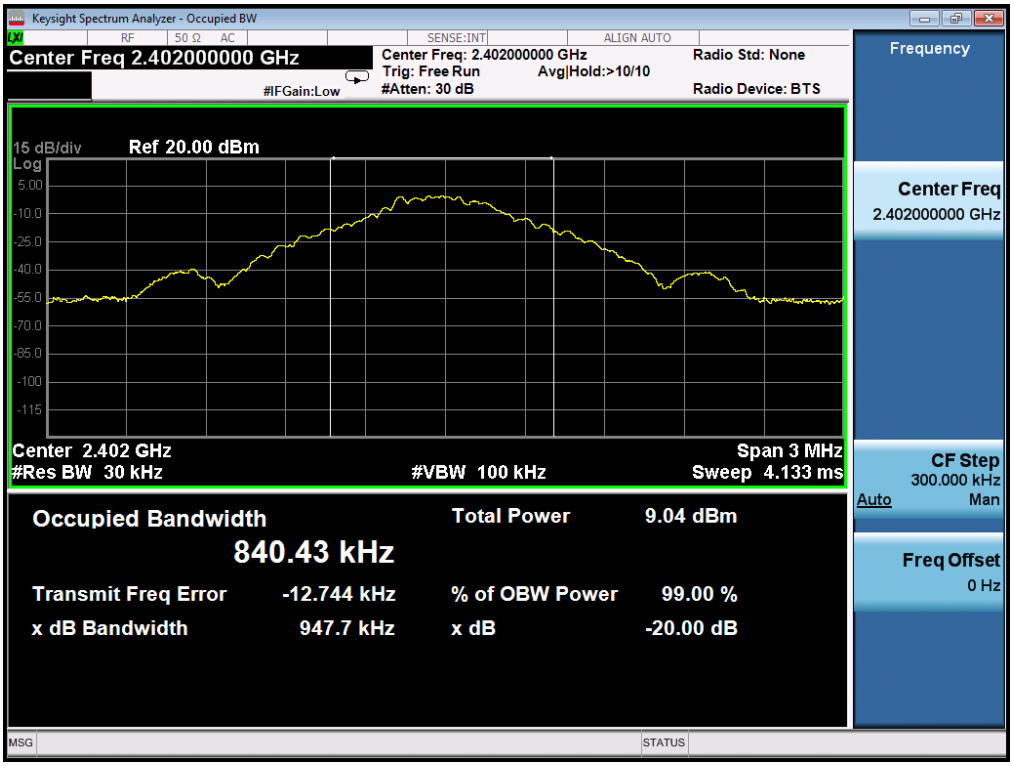
4.2. Test Set-Up (Block Diagram of Configuration)



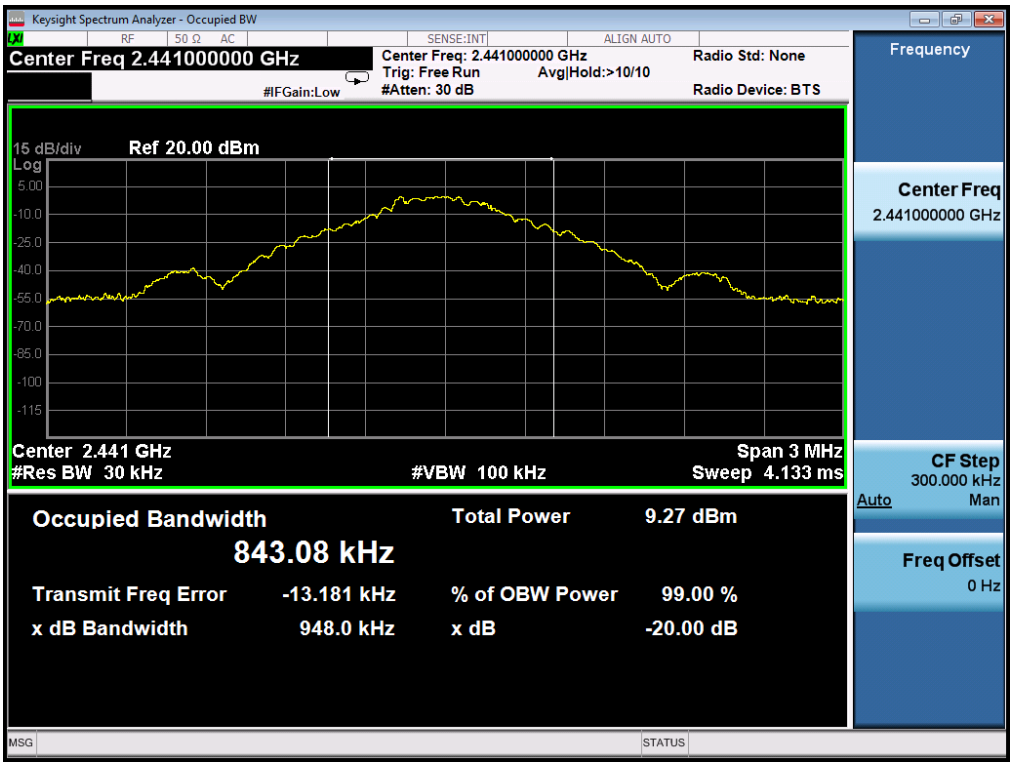
4.3. Limits and Measurement Results

MEASUREMENT RESULT FOR GFSK MOUDULATION			
Applicable Limits	Measurement Result		
	Test Data (MHz)		Criteria
N/A	Low Channel	0.9477	PASS
	Middle Channel	0.9480	PASS
	High Channel	0.9480	PASS

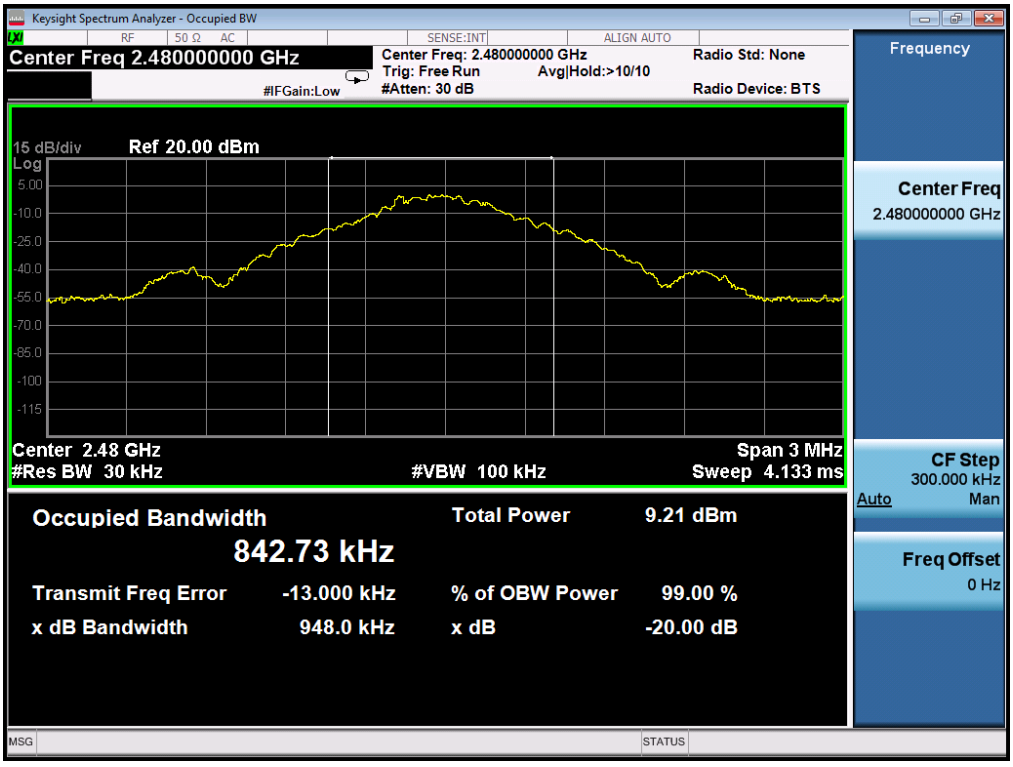
TEST PLOT OF BANDWIDTH FOR LOW CHANNEL



TEST PLOT OF BANDWIDTH FOR MIDDLE CHANNEL

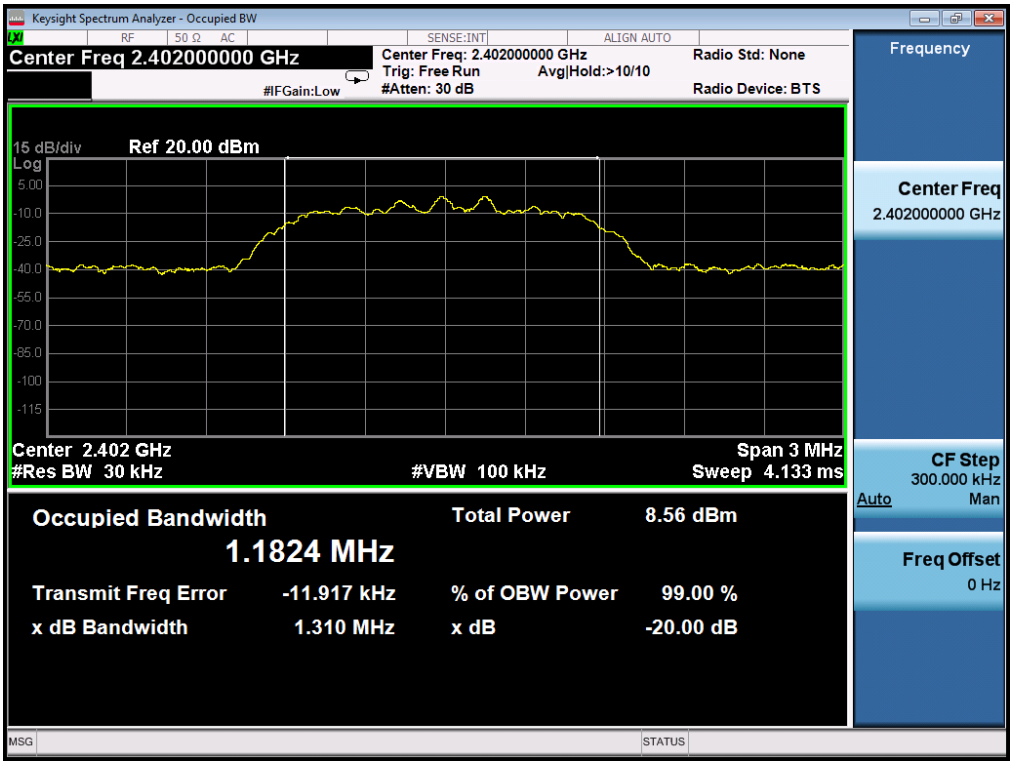


TEST PLOT OF BANDWIDTH FOR HIGH CHANNEL

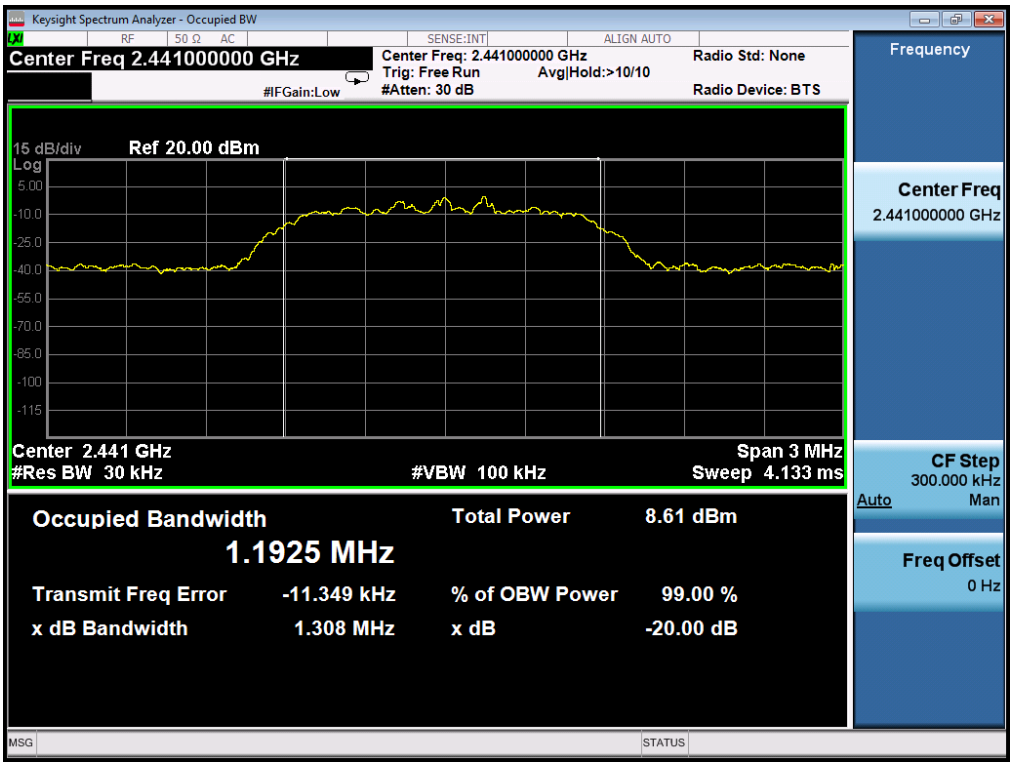


MEASUREMENT RESULT FOR Ⅱ/4-DQPSK MODULATION			
Applicable Limits	Measurement Result		
	Test Data (MHz)		Criteria
N/A	Low Channel	1.310	PASS
	Middle Channel	1.308	PASS
	High Channel	1.315	PASS

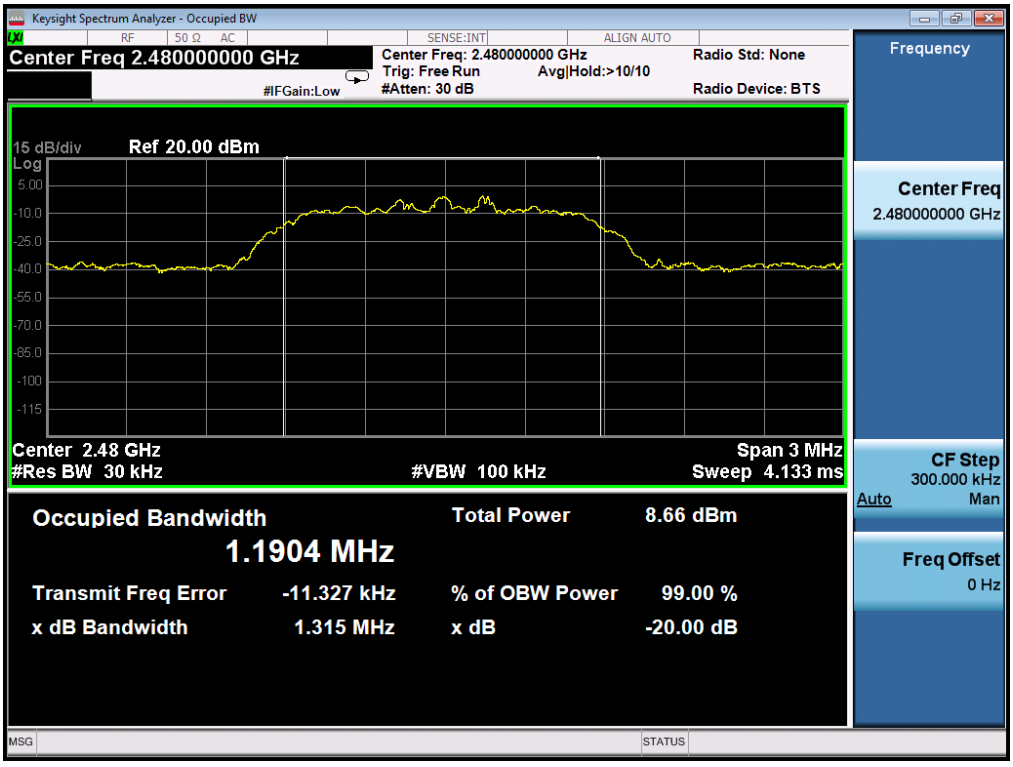
TEST PLOT OF BANDWIDTH FOR LOW CHANNEL



TEST PLOT OF BANDWIDTH FOR MIDDLE CHANNEL



TEST PLOT OF BANDWIDTH FOR HIGH CHANNEL



5. Conducted Spurious Emission

5.1. Measurement Procedure

1. Connect EUT RF output port to the Spectrum Analyzer through an RF attenuator
2. Set the EUT Work on the top, the Middle and the bottom operation frequency individually.
3. Set the Span = wide enough to capture the peak level of the in-band emission and all spurious emissions from the lowest frequency generated in the EUT up through the 10th harmonic. RBW = 100 kHz; VBW= 300 kHz; Sweep = auto; Detector function = peak.
4. Set SPA Trace 1 Max hold, then View.

5.2. Test Set-Up (Block Diagram of Configuration)

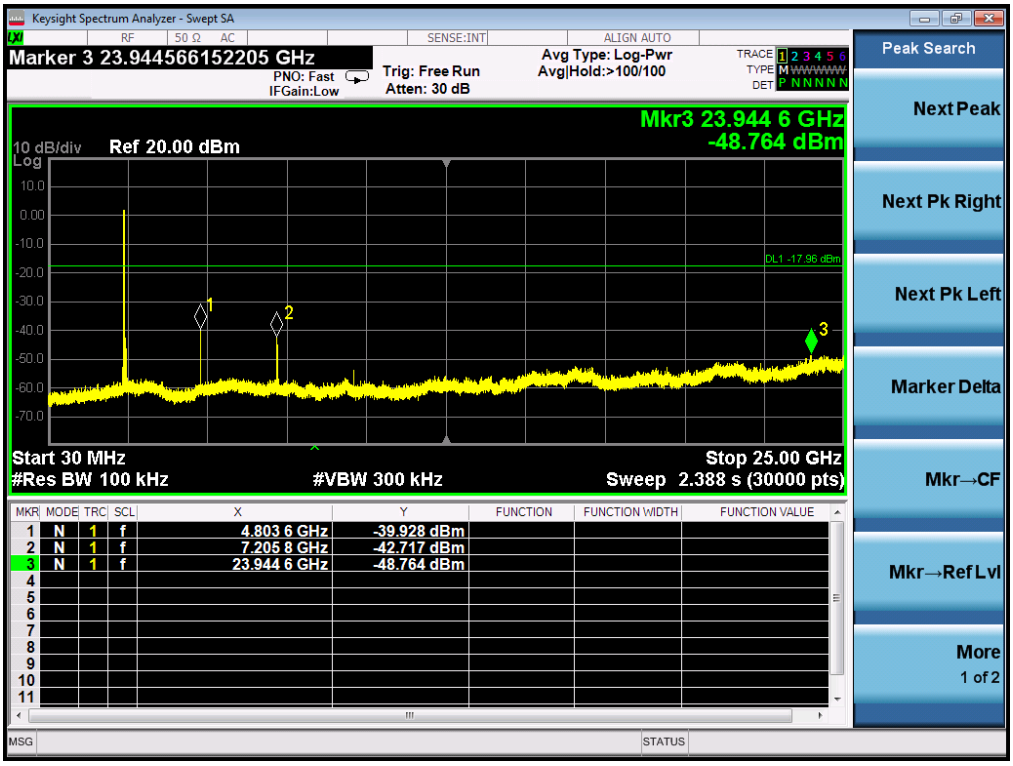
The same as described in section 4.2

5.3. Limits and Measurement Result

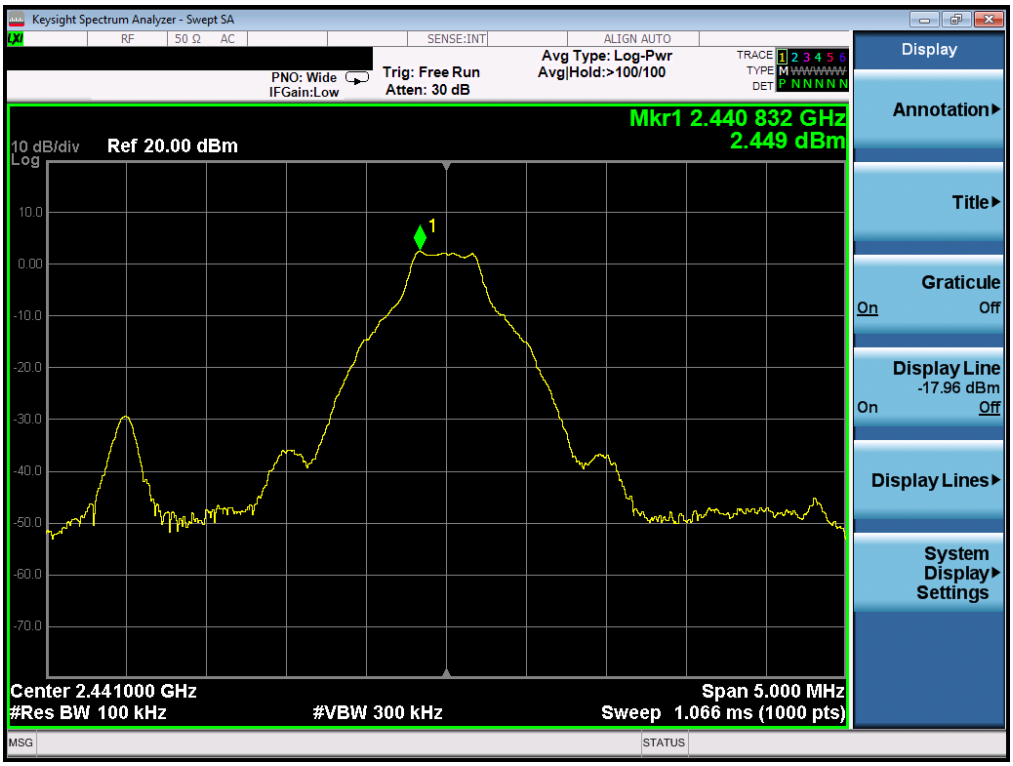
LIMITS AND MEASUREMENT RESULT		
Applicable Limits	**Measurement Result**	
	Test Data	**Criteria**
In any 100 KHz Bandwidth Outside the frequency band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produce by the intentional radiator shall be at least 20 dB below that in 100KHz bandwidth within the band that contains the highest level of the desired power. In addition, radiation emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in§15.209(a))	At least -20dBc than the limit Specified on the BOTTOM Channel	PASS
	At least -20dBc than the limit Specified on the TOP Channel	PASS

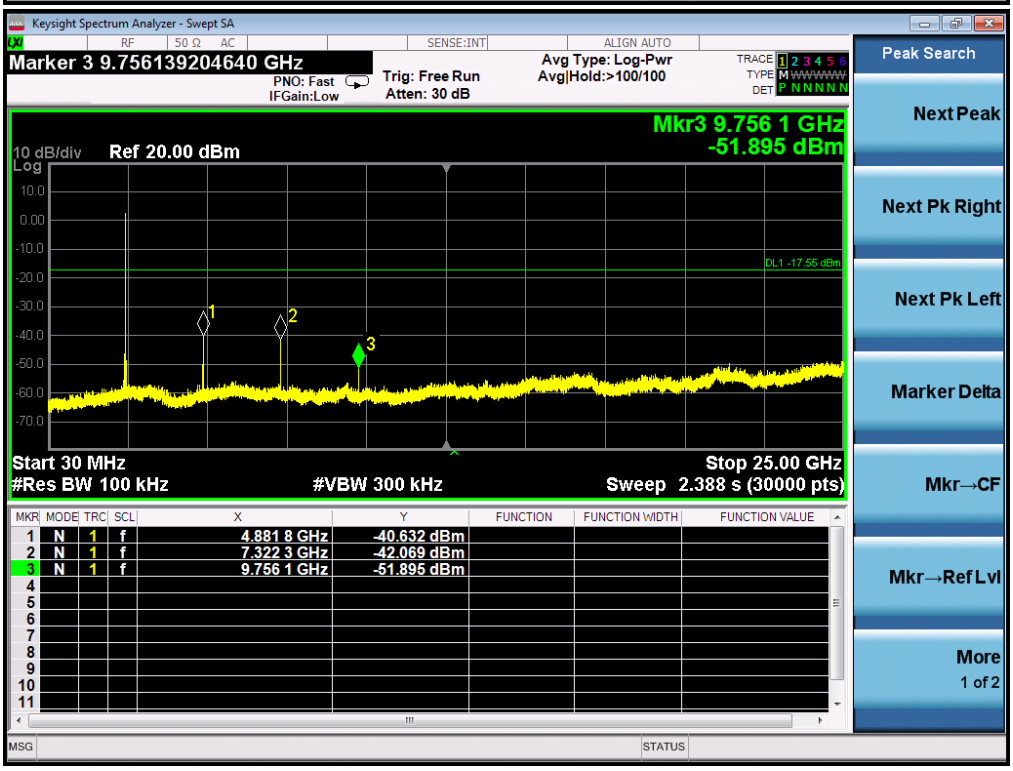
TEST RESULT FOR ENTIRE FREQUENCY RANGE

TEST PLOT OF OUT OF BAND EMISSIONS WITH THE WORST CASE OF GFSK MODULATION IN LOW CHANNEL

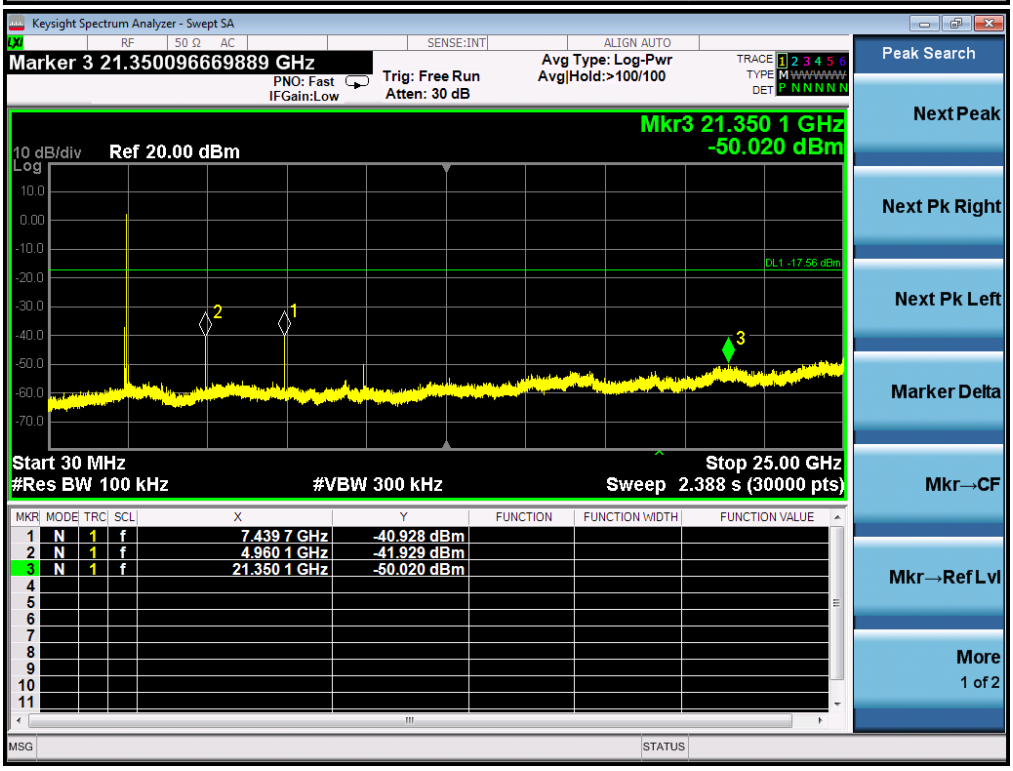


TEST PLOT OF OUT OF BAND EMISSIONS
OF GFSK MODULATION IN MIDDLE CHANNEL





TEST PLOT OF OUT OF BAND EMISSIONS
OF GFSK MODULATION IN HIGH CHANNEL

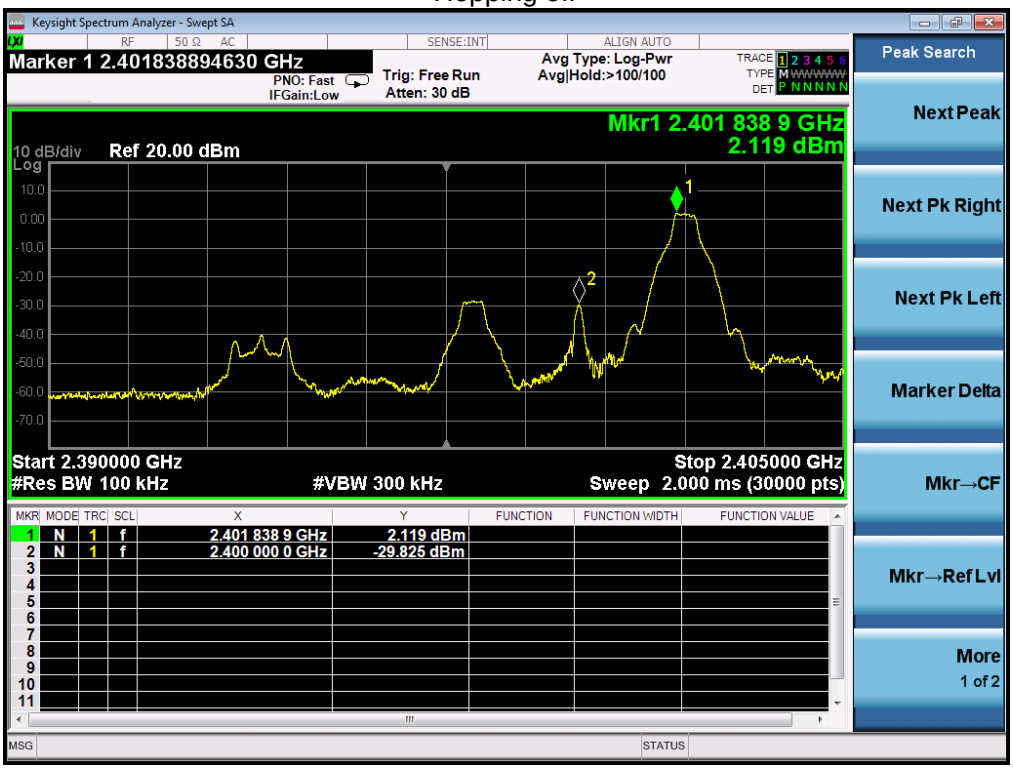


Note: The peak emissions without marker on the above plots are fundamental wave and need not to compare with the limit. The GFSK modulation is the worst case and only those data recorded in the report.

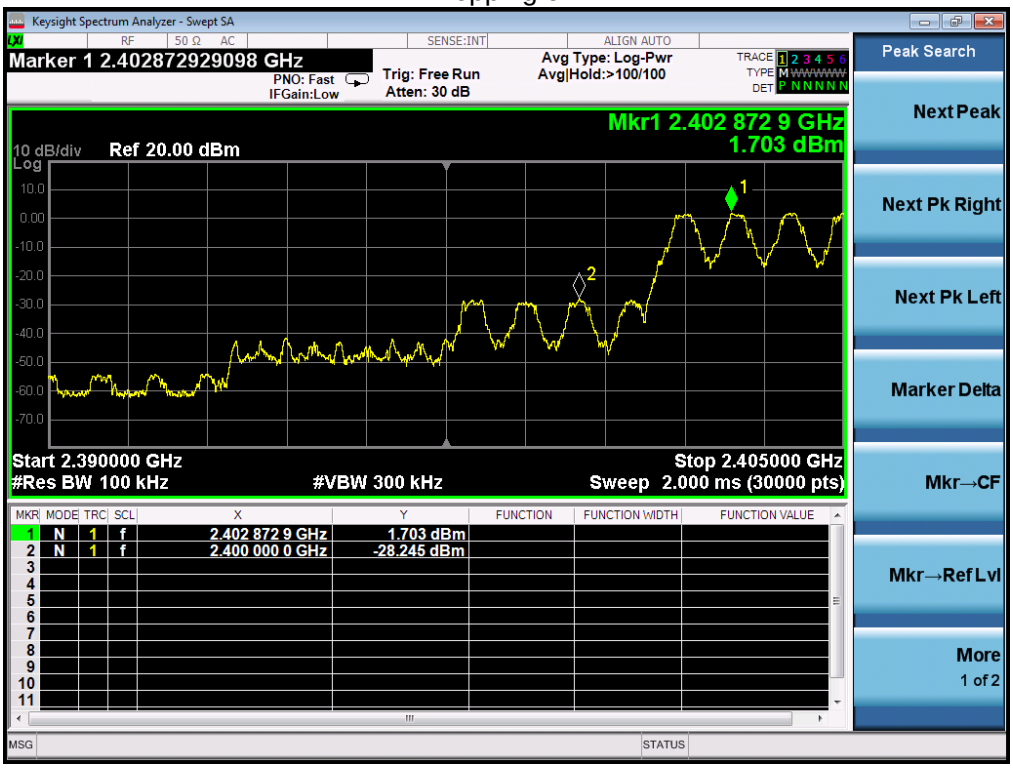
TEST RESULT FOR BAND EDGE

GFSK MODULATION IN LOW CHANNEL

Hopping off

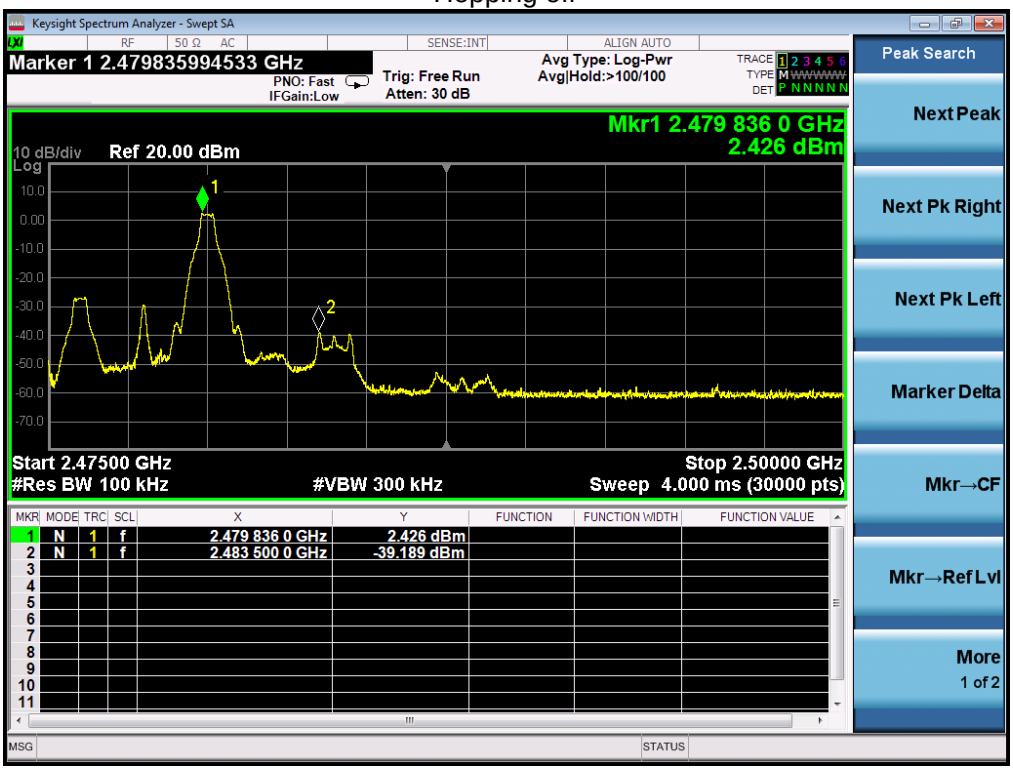


Hopping on

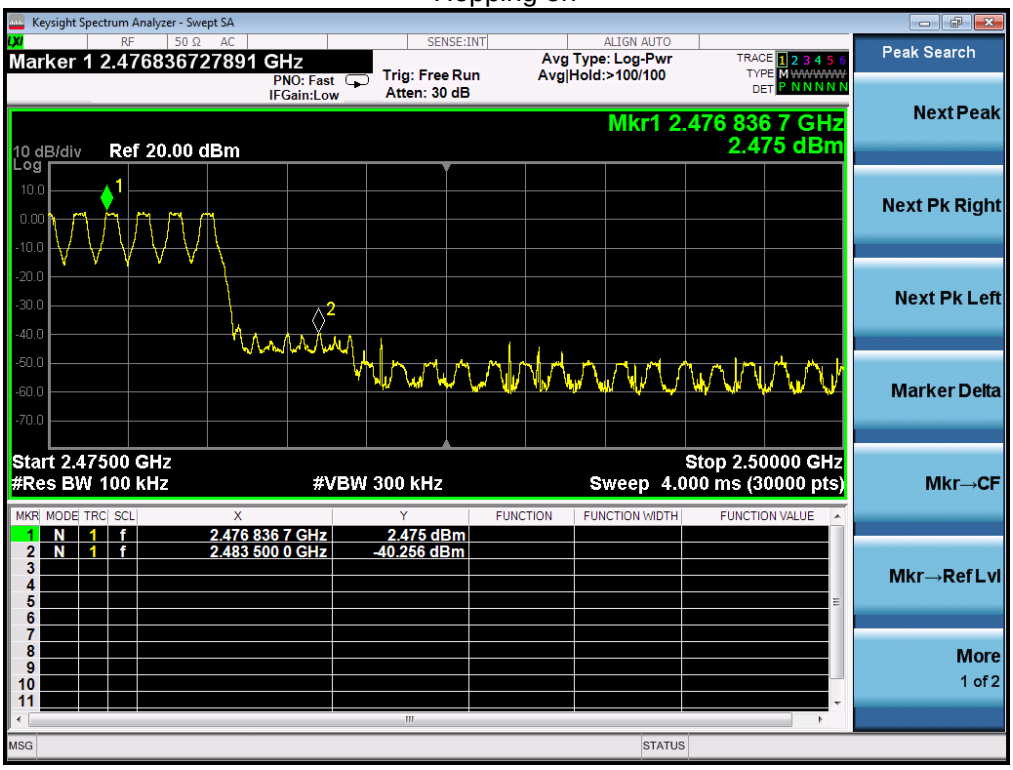


GFSK MODULATION IN HIGH CHANNEL

Hopping off



Hopping on

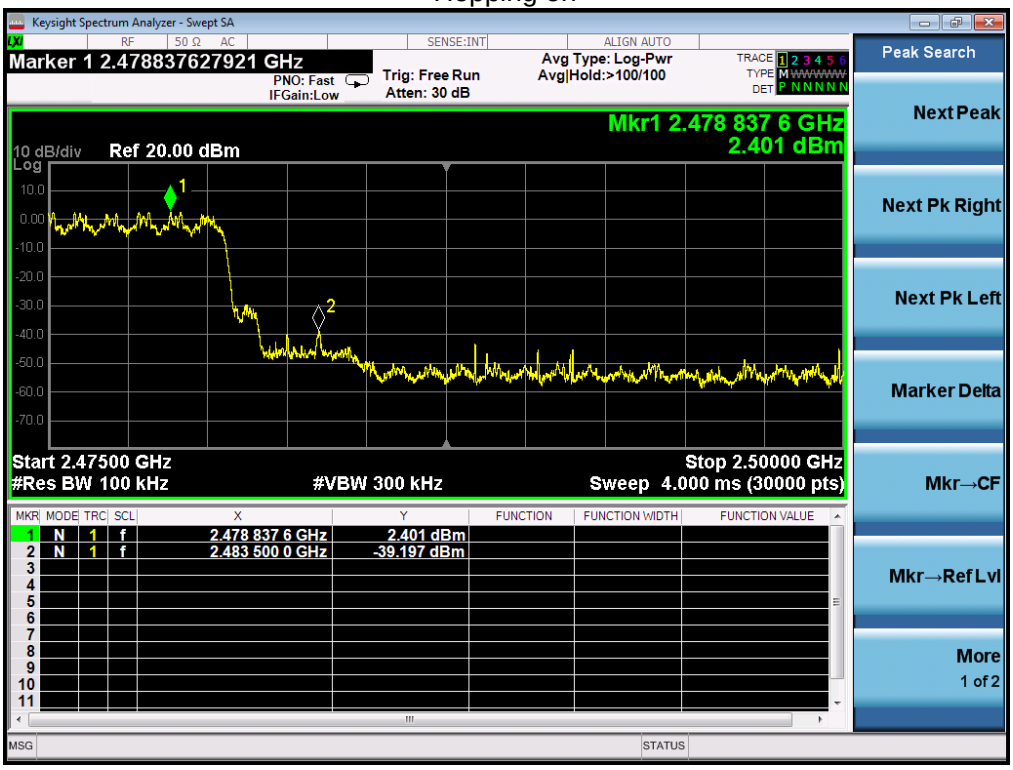


Π/4-DQPSK MODULATION IN LOW CHANNEL

Hopping off

Hopping on

Π/4-DQPSK MODULATION IN HIGH CHANNEL

Hopping off

Hopping on